Notice of References Cited Application/Control No. 10/736,475 Examiner Barry J. Gooden Jr. Applicant(s)/Patent Under Reexamination LINCOLN ET AL. Art Unit Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,601,332 A	02-1997	Schultz et al.	297/216.13
*	В	US-5,904,370 A	05-1999	Steiner et al.	280/743.1
*	O	US-6,017,059 A	01-2000	Taubenberger et al.	280/752
*	D	US-6,126,194 A	10-2000	Yaniv et al.	280/733
*	E	US-6,158,766 A	12-2000	Kowalski, Edward L.	280/730.1
*	F	US-6,217,059 B1	04-2001	Brown et al.	280/730.2
*	G	US-6,371,511 B1	04-2002	Kitagawa, Yuichi	280/730.1
*	Н	US-6,382,666 B1	05-2002	Devonport, Alex	280/733
*	-	US-6,425,602 B1	07-2002	Al-Amin et al.	280/730.2
*	٦	US-6,631,923 B2	10-2003	Eckert et al.	280/743.1
*	К	US-6,715,788 B2	04-2004	Saiguchi et al.	280/730.1
*	L	US-2004/0113399 A1	06-2004	Yoshikawa et al.	280/730.1
*	М	US-6,896,325 B2	05-2005	Takedomi et al.	297/216.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					·
	Р					
	Q	,				·
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	٥	
	>	
	8	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LINCOLN ET AL. | Examiner | Art Unit | Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,695,242 A	12-1997	Brantman et al.	297/216.1
*	В	US-6,129,376 A	10-2000	H.ang.land, Yngve	280/730.1
*	С	US-6,336,653 B1	01-2002	Yaniv et al.	280/730.1
*	D	US-2002/0020996 A1	02-2002	Eckert et al.	280/743.1
*	E	US-2002/0105176 A1	08-2002	Hammer et al.	280/733
*	F	US-6,464,246 B2	10-2002	Bayley, Gregory S.	280/728.1
*	G	US-2003/0034640 A1	02-2003	Sollars, John A. JR.	280/733
*	Н	US-2003/0151234 A1	08-2003	Ruel, Laurent	280/730.1
*	1	US-6,688,642 B2	02-2004	Sollars, Jr., John A.	280/733
*	J	US-2004/0100075 A1	05-2004	Sakai et al.	280/730.1
*	К	US-2005/0046156 A1	03-2005	Yoshikawa et al.	280/728.2
*	L	US-6,905,134 B2	06-2005	Saiguchi et al.	280/730.1
*	М	US-2005/0173899 A1	08-2005	Korechika, Koji	280/730.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0	:				
	Р				·	
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LINCOLN ET AL. | Examiner | Art Unit | Page 3 of 3 | Barry J. Gooden Jr. | 3616 | Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,466,003 A	11-1995	Tanaka et al.	280/733
*	В	US-5,474,326 A	12-1995	Cho, Sung H.	280/733
*	С	US-2002/0125701 A1	09-2002	Devonport, Alex	280/733
*	D	US-5,902,010 A	05-1999	Cuevas, Jess A.	297/216.13
*	Е	US-6,138,067 A	10-2000	Cobb et al.	701/45
*	F	US-6,220,626 B1	04-2001	Utsumi et al.	280/733
*	G	US-2002/0153715 A1	10-2002	Namiki, Hideo	280/733
*	Н	US-5,114,180	05-1992	Kami et al.	280/743.1
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	P					<u>.</u>
	Q					
	R					
	S			,		
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.